

IN THE CLAIMS:

Please cancel Claims 1 and 4 to 6 without prejudice to or disclaimer of the subject matter presented therein.

1 to 6. (Cancelled)

7. (Previously Presented) A field effect transistor having an organic semiconductor layer, comprising:

an organic semiconductor layer containing at least porphyrin; and

a layer composed of at least a polysiloxane compound, the layer being laminated on the organic semiconductor layer so as to be in intimate contact with the organic semiconductor layer,

wherein Bragg angles (2θ) of CuK α X-ray diffraction in the organic semiconductor layer have peaks at $8.3^\circ \pm 0.2^\circ$, $10.1^\circ \pm 0.2^\circ$, $11.8^\circ \pm 0.2^\circ$, and $14.4^\circ \pm 0.2^\circ$.

8. (Previously Presented) A field effect transistor having an organic semiconductor layer, comprising:

an organic semiconductor layer containing at least porphyrin; and

a layer composed of at least a polysiloxane compound, the layer being laminated on the organic semiconductor layer so as to be in intimate contact with the organic semiconductor layer,

wherein Bragg angles (2θ) of CuK α X-ray diffraction in the organic semiconductor layer have peaks at $8.4^\circ \pm 0.2^\circ$, $11.9^\circ \pm 0.2^\circ$, and $16.9^\circ \pm 0.2^\circ$.

9. (Previously Presented) A field effect transistor having an organic semiconductor layer, comprising:

- an organic semiconductor layer containing at least porphyrin; and
- a layer composed of at least a polysiloxane compound, the layer being laminated on the organic semiconductor layer so as to be in intimate contact with the organic semiconductor layer,

wherein Bragg angles (2θ) of $\text{CuK}\alpha$ X-ray diffraction in the organic semiconductor layer have peaks at $7.2^\circ \pm 0.2^\circ$, $7.8^\circ \pm 0.2^\circ$, $11.7^\circ \pm 0.2^\circ$, and $23.5^\circ \pm 0.2^\circ$.

10. (Previously Presented) A field effect transistor having an organic semiconductor layer, comprising:

- an organic semiconductor layer containing at least porphyrin; and
- a layer composed of at least a polysiloxane compound, the layer being laminated on the organic semiconductor layer so as to be in intimate contact with the organic semiconductor layer,

wherein Bragg angles (2θ) of $\text{CuK}\alpha$ X-ray diffraction in the organic semiconductor layer have peaks at $7.3^\circ \pm 0.2^\circ$, $7.8^\circ \pm 0.2^\circ$, $11.7^\circ \pm 0.2^\circ$, and $19.6^\circ \pm 0.2^\circ$.

11 to 37. (Cancelled)